

**Search Notes**

Application/Control No.

10/799,918

Examiner

John A. Tweel, Jr.

Applicant(s)/Patent under  
Reexamination

KANG ET AL.

Art Unit

2636

**SEARCHED**

Class	Subclass	Date	Examiner
340	566	12/7/2005	JAT
345	179	12/7/2005	JAT
	169	12/8/2005	JAT
178	18.01	12/8/2005	JAT
	18.03	12/8/2005	JAT
	19.01	12/8/2005	JAT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR